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3.3 V, 62.5 MHz / 125 MHz LVPECL Clock Oscillator

The NBXDBA014 dual frequency crystal oscillator (XO) is designed to meet today's requirements for 3.3 V LVPECL clock generation applications. The device uses a high Q fundamental crystal and Phase Lock Loop (PLL) multiplier to provide selectable 62.5 MHz or 125 MHz, ultra low jitter and phase noise LVPECL differential output. This device is a member of ON Semiconductor's PureEdgeTM clock family that provides accurate and precision clock solutions.

Available in 5 mm x 7 mm SMD (CLCC) package on 16 mm tape and reel in quantities of 1,000.

Features

- LVPECL Differential Output
- Uses High Q Fundamental Mode Crystal and PLL Multiplier
- Ultra Low Jitter and Phase Noise 0.4 ps (12 kHz 20 MHz)
- Selectable Output Frequency 62.5 MHz (default) / 125 MHz
- Total Frequency Stability ±50 PPM
- Hermetically Sealed Ceramic SMD Package
- RoHS Compliant
- Operating Range 3.3 V ±10%
- This is a Pb–Free Device

Applications

- Fiber Distributed Data Interface
- Ethernet, Gigabit Ethernet
- Infiniband
- PCIe
- Host Bus Adapter
- RAID Controller



Figure 1. Simplified Logic Diagram



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DBA014	$4 = NBXDBA014 (\pm 50 PPM)$				
62.5/12	62.5/125.0 = Output Frequency				
AA	= Assembly Location				
WL	= Wafer Lot				
YY	= Year				
WW	= Work Week				
G	= Pb-Free Package				
	-				

ORDERING INFORMATION

Device	Package	Shipping [†]
NBXDBA014LN1TA0	G CLCC-6 (Pb-Free)	1000/Tape & Reel
NBXDBA014LNHTA	G CLCC-6 (Pb-Free)	100/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.



Figure 2. Pin Connections (Top View)

Table 1. PIN DESCRIPTION

Pin No.	Symbol	I/O	Description	
1	OE	LVTTL/LVCMOS Control Input	Output Enable Pin. When left floating pin defaults to logic HIGH and output is active. See OE pin description Table 2.	
2	FSEL	LVTTL/LVCMOS Control Input	Output Frequency Select Pin. Pin will default to logic HIGH when left open. See Output Frequency Select pin description Table 3.	
3	GND	Power Supply	Ground 0 V	
4	CLK	LVPECL Output	Non–Inverted Clock Output. Typically loaded with 50 Ω receiver termination resistor to V_{TT} = V_{DD} – 2 V.	
5	CLK	LVPECL Output	Non–Inverted Clock Output. Typically loaded with 50 Ω receiver termination resistor to V_{TT} = V_{DD} – 2 V.	
6	V _{DD}	Power Supply	Positive power supply voltage. Voltage should not exceed 3.3 V \pm 10%.	

Table 2. OUTPUT ENABLE TRI-STATE FUNCTION

OE Pin	Output Pin
Open	Active
HIGH Level	Active
LOW Level	High Z

Table 3. OUTPUT FREQUENCY SELECT

FSEL Pin	Output Frequency (MHz)
Open (pin will float high)	62.5
HIGH Level	62.5
LOW Level	125

Table 4. ATTRIBUTES

Characteristic		Value	
ESD Protection	Human Body Model Machine Model	2 kV 200 V	
Meets or Exceeds JEI	Meets or Exceeds JEDEC Standard EIA/JESD78 IC Latchup Test		

1. For additional Moisture Sensitivity information, refer to Application Note AND8003/D.

Table 5. MAXIMUM RATINGS

Symbol	Parameter	Condition 1	Condition 2	Rating	Units
V _{DD}	Positive Power Supply	GND = 0 V		4.6	V
l _{out}	LVPECL Output Current	Continuous Surge		25 50	mA
T _A	Operating Temperature Range			-40 to +85	°C
T _{stg}	Storage Temperature Range			–55 to +120	°C
T _{sol}	Wave Solder	See Figure 6		260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

Table 6. DC CHARACTERISTICS (V_{DD} = 3.3 V ± 10%,	, GND = 0 V, $T_A = -40^{\circ}C$ to +85°C)
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Symbol	Characteristic	Conditions	Min.	Тур.	Max.	Units
I _{DD}	Power Supply Current (Note 2)			50	65	mA
V _{IH}	OE and FSEL Input HIGH Voltage		2000		V _{DD}	mV
V _{IL}	OE and FSEL Input LOW Voltage		GND – 300		800	mV
I _{IH}	Input HIGH Current OE FSEL		-100 -100		+100 +100	μΑ
Ι _{ΙL}	Input LOW Current OE FSEL		-100 -100		+100 +100	μΑ
V _{OH}	Output HIGH Voltage (Note 2)	V _{DD} = 3.3 V	V _{DD} -1145 2155		V _{DD} -895 2405	mV
V _{OL}	Output LOW Voltage (Note 2)	V _{DD} = 3.3 V	V _{DD} -1945 1355		V _{DD} -1600 1700	mV
V _{OUTPP}	Output Voltage Amplitude (Note 2)			780		mV

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

2. Measurement taken with outputs terminated with 50 ohm to V_{DD}-2 V.

Table 7. AC CHARACTERISTICS (V_{DD} = 3.3 V ± 10%, GND = 0 V, T_A = -40°C to +85°C) (Note 3)

Symbol	Characteristic	Conditions	Min.	Тур.	Max.	Units
fclkout	Output Clock Frequency	FSEL = HIGH		62.5		MHz
		FSEL = LOW		125		
Δf	Frequency Stability NBXDBA014	(Note 4)			±50	ppm
Φ_{NOISE}	Phase-Noise Performance	100 Hz of Carrier		-111/104		dBc/Hz
	f _{CLKout} = 62.5 MHz/125 MHz	1 kHz of Carrier		-129/-123		dBc/Hz
		10 kHz of Carrier		-138/-132		dBc/Hz
		100 kHz of Carrier		-141/-135		dBc/Hz
		1 MHz of Carrier		-141/-135		dBc/Hz
		10 MHz of Carrier		-159/-156		dBc/Hz
t _{jit} (Φ)	RMS Phase Jitter	12 kHz to 20 MHz		0.4	0.9	ps
t _{jitter}	Cycle to Cycle, RMS	1000 Cycles		3	10	ps
	Cycle to Cycle, Peak-to-Peak	1000 Cycles		15	35	ps
	Period, RMS	10,000 Cycles		2	5	ps
	Period, Peak-to-Peak	10,000 Cycles		10	25	ps
t _{OE/OD}	Output Enable/Disable Time				200	ns
^t DUTY_CYCLE	Output Clock Duty Cycle (Measured at Cross Point)		48	50	52	%
t _R	Output Rise Time (20% and 80%)			380	620	ps
t _F	Output Fall Time (80% and 20%)			400	620	ps
t _{start}	Start-up Time			1	5	ms
	Aging	1 st Year			3	ppm
		Every Year After 1st			1	ppm

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

3. Measurement taken with outputs terminated with 50 ohm to V_{DD} -2 V.

4. Parameter guarantees 10 years of aging. Includes initial stability at 25°C, shock, vibration, and first year aging.

Table 8. RELIABILITY COMPLIANCE

Parameter	Standard	Method
Shock	Mechanical	MIL-STD-833, Method 2002, Condition B
Solderability	Mechanical	MIL-STD-833, Method 2003
Vibration	Mechanical	MIL-STD-833, Method 2007, Condition A
Solvent Resistance	Mechanical	MIL-STD-202, Method 215
Thermal Shock	Environment	MIL-STD-833, Method 1011, Condition A
Moisture Level Sensitivity	Environment	MSL1 260°C per IPC/JEDEC J-STD-020D



Figure 3. Typical Phase Noise Plot of the NBXDBA014 Operating at 62.5 MHz



Figure 4. Typical Phase Noise Plot of the NBXDBA014 Operating at 125 MHz



Figure 5. Typical Termination for Output Driver and Device Evaluation (See Application Note AND8020/D – Termination of ECL Logic Devices.)



Figure 6. Recommended Reflow Soldering Profile

PACKAGE DIMENSIONS

6 PIN CLCC, 7x5, 2.54P CASE 848AB-01 ISSUE A



NOTES:

1. DIMENSIONING AND TOLERANCING PER

ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: MILLIMETERS.

	MILLIMETERS		
DIM	MIN	NOM	MAX
Α	1.70	1.80	1.90
A1		0.70 REF	
A2		0.36 REF	
A3	0.08	0.10	0.12
b	1.30	1.40	1.50
D		7.00 BSC	
D1	6.17	6.20	6.23
D2	6.66	6.81	6.96
D3	5.08 BSC		
Е		5.00 BSC	
E1	4.37	4.40	4.43
E2	4.65	4.80	4.95
E3	3.49 BSC		
e	2.54 BSC		
L	1.17	1.27	1.37
R		0.70 REF	

SOLDERING FOOTPRINT*



*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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